

Notice of References Cited	Application/Control No. 10/611,314	Applicant(s)/Patent Under Reexamination PEKAREK ET AL.	
	Examiner Shambhavi Patel	Art Unit 2128	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Kim et al. 'Full Software Analysis and Impedance Matching of Radio Frequency CMOS Integrated Circuits'. Volume 23, March 2000. pages 183-189
	V	Eo et al. "Generalized Coupled Interconnect Transfer Function and High-Speed Signal Simulations" IEEE Transactions of Microwave Theory and Techniques, Vol. 43 No. 5 May 1995.
	W	Bockelman et al. "Combined Differential and Common-Mode Scattering Parameters: Theory and Simulation" IEEE Transactions on Microwave Theory and Techniques, Vol. 43 No. 7 July 1995.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.